

## **Search Notes**



**Application/Control No.**

10/708,827

Examiner

Daniel I. Walsh

**Applicant(s)/Patent under  
Reexamination**

BEENAU ET AL.

## **Art Unit**

2876

**SEARCHED**

# **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner